

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/715,686	ONISHI ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Cheukfan Lee	2625	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0159393 A1	07-2006	Ikeda, Makoto	385/031
*	B	US-2006/0152805 A1	07-2006	Ikeda et al.	359/515
*	C	US-6,892,945	05-2005	Shishido, Kazuo	235/454
*	D	US-7,136,203	11-2006	Yokota et al.	358/484
*	E	US-7,042,599	05-2006	Yokota et al.	358/475
*	F	US-6,333,779	12-2001	Tabata et al.	355/68
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.